

PROBE LAP® PRODUCT DESCRIPTION



GENERAL

Probe Lap[®] is used as a direct replacement for on-line lapping film applications. It is built using aluminum-oxide or silicon-carbide abrasive particles. The sheets can be mounted on various substrates and abrasion plates used for on-line and off-line probe cleaning.

Standard Probe Lap[®] cleaning wafers and cleaning sheets have an operating temperature range -50C to 125C. With additional processing, tempered Probe Lap[®] high temperature capable cleaning wafers and cleaning sheets can be used at test temperatures up to -50C to 150C. Ultra-Temp Probe Lap sheets and wafers have a maximum operating temperature of 200C.

	Material	Material	Nominal	Operat		ating Temperature		
Material	Designation	Color	Abrasive	-50C	25C	125C	150C	200C
Probe Lap (Standard)	PL-xAH (AIO)	Yellow	0.5 μm		0	0		
		Purple	1 μm	0				
		Green	3 μm					
	PL-xSH (SiC)	Light Gray	1 μm					
		Dark Gray	3 μm					
Probe Lap (High Temp)	PL-xAT (AIO)	Yellow	0.5 μm		0	0	0	
		Purple	1 μm					
		Green	3 μm	0				
	PL-xST (SiC)	Light Gray	1 μm					
		Dark Gray	3 μm					
Probe Lap (Ultra Temp)	PL-xAHT (AIO)	Brown Gray	1 μm	0	0	0	0	
			3 μm					0
	PL-xSHT (SiC)		<u>1 μm</u>					
			3 µm					

CROSS SECTION



	Cleaning Material Configuration						
	Sheet	200mm Wafer	300mm Wafer	Custom Install			
Support Carrier		725 ± 20μm (SEMI Standard)	775 ± 20µm (SEMI Standard)	Contact ITS			
Total Installed Stack Height	112 ± 12 μm	837 ± 32μm	887 ± 32 μm	Contact ITS			

 $\mathsf{PROBE}\;\mathsf{LAP}^{\circledast}$ is registered trademark of International Test Solutions.

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